

<b>Notice of References Cited</b>	Application/Control No. 10/781,210		Applicant(s)/Patent Under Reexamination NAKANISHI, TOSHIKI	
	Examiner TAN TRINH		Art Unit 2618	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,345,188	02-2002	Keskitalo et al.	455/561
*	B	US-6,091,788	07-2000	Keskitalo et al.	375/347
*	C	US-2002/0150065	10-2002	Ponnekanti, Seshaiiah	370/334
*	D	US-5,870,681	02-1999	Myer, Robert Evan	455/562.1
*	E	US-2002/0032015	03-2002	Kitakado et al.	455/277.1
*	F	US-2001/0031648	10-2001	Proctor et al.	455/562
*	G	US-7,072,325	07-2006	Sato, Toshifumi	370/342
*	H	US-2005/0083875	04-2005	Sato, Toshifumi	370/328
*	I	US-2007/0123262	05-2007	Proctor, James A. JR.	455/442
*	J	US-2002/0039886	04-2002	Doi, Yoshiharu	455/25
*	K	US-2003/0153361	08-2003	Mori et al.	455/562
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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